

Electronic supplementary information

Nanoscale interface engineering in ZnO twin nanorods for proposed phonon tunnel devices

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We have shown EDX data collected from area 1 (not included in manuscript). Cu and C signal is due to carbon coated Cu-grid. Drift corrected EDX line profile along line 2 was collected while beam of about 1 nm is scanning across about 1400 nm length. In this process X-rays were collected point by point from 300 points in one direction from the STEM-HAADF image shown in figure. Which means we have collected data every $(1400\text{nm}/300) = 4.6$ nm distance. But in case of EDX and thick sample the interaction volume is large.

